Cut-and-Paste Editing of Multiresolution Surfaces

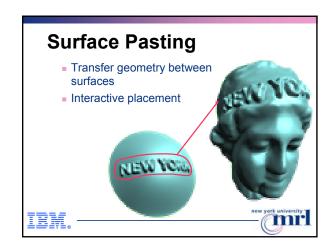
Henning Biermann, Ioana Martin, Fausto Bernardini, Denis Zorin

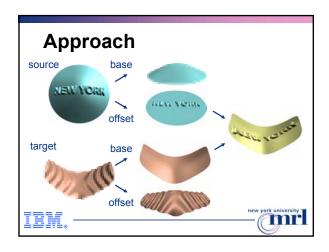
NYU Media Research Lab

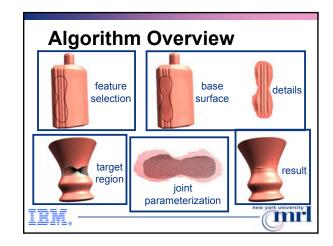
IBM T. J. Watson Research Center

IEM









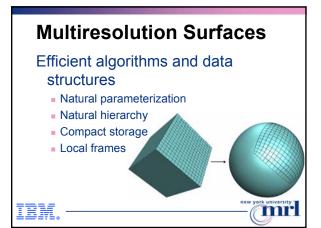
Spline pasting Forsey [88], Barghiel [95], Mann [97] Base/detail separation Kobbelt [98], Guskov [99], Lee [00] Surface parameterization

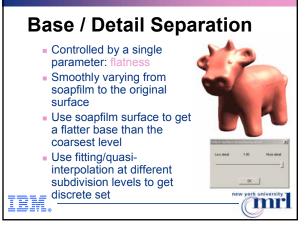
Related Work

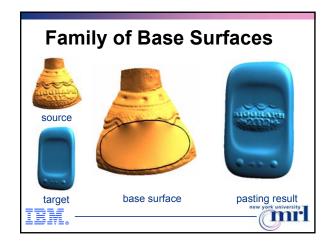
 Eck [95], Pedersen [95,96], Floater [97], Guskov [00], Sheffer [00], Desbrun [02], Levy [02]

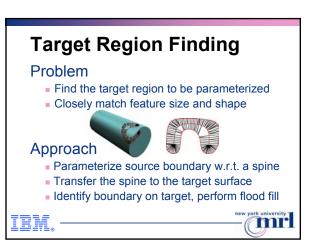
IBM.

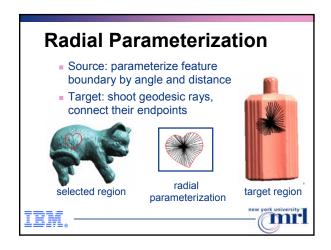


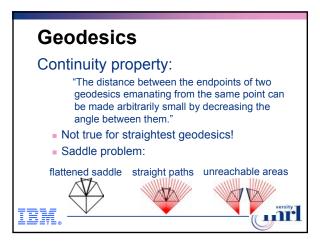


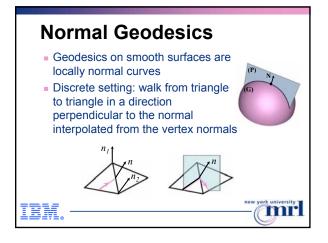


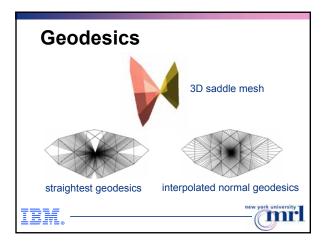


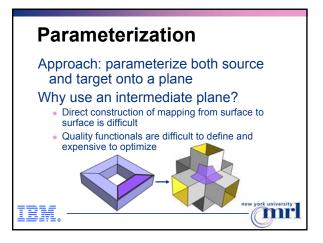












Requirements

- One-to-one for resampling purposes
- Minimize distortion
- Free boundary





selected feature parameterization

 Until recently, nothing available; now several options: Sheffer '00, Desbrun '02, Levy'02

Angle-Based Flattening

(Sheffer & de Sturler'00)

Use angles as variables:

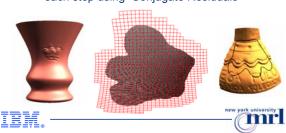
- Set target angles φ_t^v so that at each vertex v angles sum up to 2π (scale angles by $2\pi l \sum_t \alpha_t^v$)
- Optimize $\sum_{t,v} \mathbf{w}_t^{v} (\alpha_t^{v} \phi_t^{v})^2$ subject to constraints

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Nonlinear Optimization

- The flatter the mesh, the faster it converges
- Use Newton iteration, solve a linear system at each step using Conjugate Residuals



Resampling

On the common parameterization:

- Resample source details at target vertex positions in parametric domain
- Point location + evaluation (bilinear or subdivision)
- Use differentials to transform details

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